Model: EC-80P
Sheet resistance/resistivity measurement instrument
[Hand held probe type, Eddy current method]

Features

- Auto-measurement start by probe head contacting to sample
- 3 measurement modes for wafer resistivity, bulk resistivity and sheet resistance
- Easy set up to measurement condition by JOG dial
- 5 types of probe for each measuring range
- Resistivity probe can be changed by sample’s resistivity range
  (*Option; 2nd & 3rd probe types)
- Measurement spot size (probe core size): 14mmφ
- <Option> PN type checker probe
  (*PN Checking range in resistivity: 0.1 - 1,000 ohm.cm)

Applications

Any sample within the measurement range can be measured.
- Wafer sample;
  Si, Compound(GaN,GaP), Epitaxial, Diffusion, SiC, etc
- Thin film layer;
  Semiconductor process, Metal, ITO, IZO, Low-E glass, LED/OLED etc
- Others

Sample sizes

Any size and shape can be measured.
 (*Larger than measurement spot size)
## Measurement Range

<table>
<thead>
<tr>
<th>Probe Type</th>
<th>Measurement Range</th>
</tr>
</thead>
<tbody>
<tr>
<td>(1) Low</td>
<td>0.01 - 0.5 ohm/sq (0.001 - 0.05 ohm.cm)</td>
</tr>
<tr>
<td>(2) Middle</td>
<td>0.5 - 10 ohm/sq (0.05 - 0.5 ohm.cm)</td>
</tr>
<tr>
<td>(3) High</td>
<td>10 - 1000 ohm/sq (0.5 – 60 ohm.cm)</td>
</tr>
<tr>
<td>(4) Super High</td>
<td>1000 - 3000 ohm/sq (60 – 180 ohm.cm)</td>
</tr>
<tr>
<td>(5) Solar wafer</td>
<td>5 - 500 ohm/sq (0.2 – 15 ohm.cm)</td>
</tr>
</tbody>
</table>

*Resistivity range for each probe type(ohm.cm) assumed thickness : 200μm.

## Measurement Repeatability

<table>
<thead>
<tr>
<th>Measurement Range</th>
<th>%</th>
</tr>
</thead>
<tbody>
<tr>
<td>Low, Middle</td>
<td>≤ 1.0 %</td>
</tr>
<tr>
<td>High (10 – 400 ohm/sq)</td>
<td>≤ 1.0 %</td>
</tr>
<tr>
<td>High (400 – 1000 ohm/sq)</td>
<td>≤ 2.0 %</td>
</tr>
<tr>
<td>Super High</td>
<td>≤ 4.0 %</td>
</tr>
<tr>
<td>Solar wafer</td>
<td>≤ 1.5 %</td>
</tr>
</tbody>
</table>

*CV = STDEVP/AVG × 100%
Repeatability by each ohm/sq (% of one sigma) and 10 times measurement (same site of the certified area of NIST and/or VLSI standards).

## Dimensions & Utilities

<Dimensions> Main body : W255 × D275 × H95mm, 4kg
Handy probe : 20mmΦ x 80mm

<Utilities> AC100V±10%, 50/60Hz, 100VA

*Please contact us for more details.
*The customers are always welcome to do Demo measurement.
*Specification subject to change without notice.

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